


<b>Search Notes</b>  	<b>Application/Control No.</b>  09814050	<b>Applicant(s)/Patent Under Reexamination</b>  OHKI ET AL.
	<b>Examiner</b>  Nguyen, Jennifer T	<b>Art Unit</b>  2629

SEARCHED			
Class	Subclass	Date	Examiner
345	156,157,169	9/20/08	JN

SEARCH NOTES		
Search Notes	Date	Examiner
east, IEEE, JPO, PG-PUB	9/20/08	JN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
455	550,566	9/20/08	JN

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